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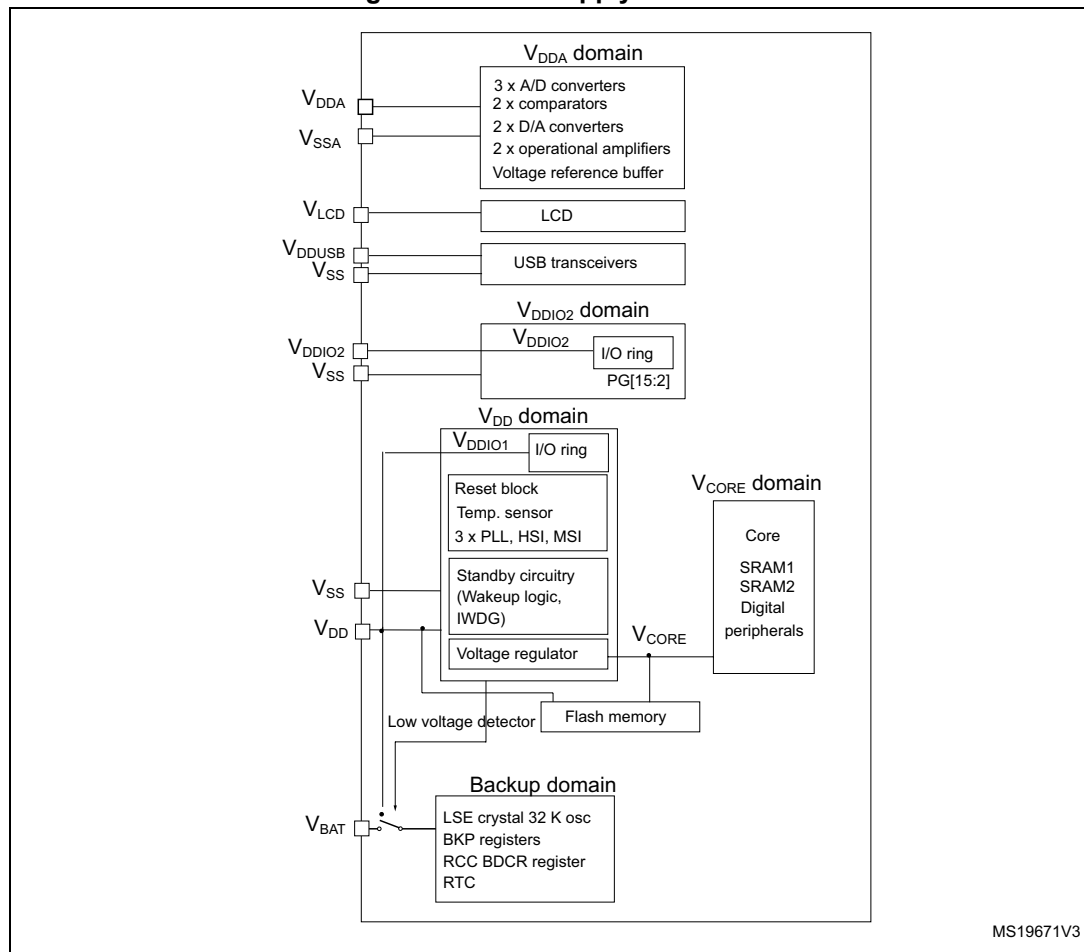
Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex® -M4
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	CANbus, EBI/EMI, I ² C, IrDA, LINbus, MMC/SD, QSPI, SAI, SPI, SWPMI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, LCD, PWM, WDT
Number of I/O	109
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 19x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	132-UFBGA
Supplier Device Package	132-UFBGA (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l476qgi6tr

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Figure 2. Power supply overview



3.9.2 Power supply supervisor

The device has an integrated ultra-low-power brown-out reset (BOR) active in all modes except Shutdown and ensuring proper operation after power-on and during power down. The device remains in reset mode when the monitored supply voltage V_{DD} is below a specified threshold, without the need for an external reset circuit.

The lowest BOR level is 1.71V at power on, and other higher thresholds can be selected through option bytes. The device features an embedded programmable voltage detector (PVD) that monitors the V_{DD} power supply and compares it to the VPVD threshold. An interrupt can be generated when V_{DD} drops below the VPVD threshold and/or when V_{DD} is higher than the VPVD threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

In addition, the device embeds a Peripheral Voltage Monitor which compares the independent supply voltages V_{DDA} , V_{DDUSB} , V_{DDIO2} with a fixed threshold in order to ensure that the peripheral is in its functional supply range.

3.23 Random number generator (RNG)

All devices embed an RNG that delivers 32-bit random numbers generated by an integrated analog circuit.

3.24 Timers and watchdogs

The STM32L476 includes two advanced control timers, up to nine general-purpose timers, two basic timers, two low-power timers, two watchdog timers and a SysTick timer. The table below compares the features of the advanced control, general purpose and basic timers.

Table 10. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
Advanced control	TIM1, TIM8	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	3
General-purpose	TIM2, TIM5	32-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM3, TIM4	16-bit	Up, down, Up/down	Any integer between 1 and 65536	Yes	4	No
General-purpose	TIM15	16-bit	Up	Any integer between 1 and 65536	Yes	2	1
General-purpose	TIM16, TIM17	16-bit	Up	Any integer between 1 and 65536	Yes	1	1
Basic	TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

3.24.1 Advanced-control timer (TIM1, TIM8)

The advanced-control timer can each be seen as a three-phase PWM multiplexed on 6 channels. They have complementary PWM outputs with programmable inserted dead-times. They can also be seen as complete general-purpose timers. The 4 independent channels can be used for:

- Input capture
- Output compare
- PWM generation (edge or center-aligned modes) with full modulation capability (0-100%)
- One-pulse mode output

In debug mode, the advanced-control timer counter can be frozen and the PWM outputs disabled to turn off any power switches driven by these outputs.

Many features are shared with those of the general-purpose TIMx timers (described in [Section 3.24.2](#)) using the same architecture, so the advanced-control timers can work together with the TIMx timers via the Timer Link feature for synchronization or event chaining.

3.24.2 General-purpose timers (TIM2, TIM3, TIM4, TIM5, TIM15, TIM16, TIM17)

There are up to seven synchronizable general-purpose timers embedded in the STM32L476 (see [Table 10](#) for differences). Each general-purpose timer can be used to generate PWM outputs, or act as a simple time base.

- TIM2, TIM3, TIM4 and TIM5

They are full-featured general-purpose timers:

- TIM2 and TIM5 have a 32-bit auto-reload up/downcounter and 32-bit prescaler
- TIM3 and TIM4 have 16-bit auto-reload up/downcounter and 16-bit prescaler.

These timers feature 4 independent channels for input capture/output compare, PWM or one-pulse mode output. They can work together, or with the other general-purpose timers via the Timer Link feature for synchronization or event chaining.

The counters can be frozen in debug mode.

All have independent DMA request generation and support quadrature encoders.

- TIM15, 16 and 17

They are general-purpose timers with mid-range features:

They have 16-bit auto-reload upcounters and 16-bit prescalers.

- TIM15 has 2 channels and 1 complementary channel
- TIM16 and TIM17 have 1 channel and 1 complementary channel

All channels can be used for input capture/output compare, PWM or one-pulse mode output.

The timers can work together via the Timer Link feature for synchronization or event chaining. The timers have independent DMA request generation.

The counters can be frozen in debug mode.

3.24.3 Basic timers (TIM6 and TIM7)

The basic timers are mainly used for DAC trigger generation. They can also be used as generic 16-bit timebases.

3.24.4 Low-power timer (LPTIM1 and LPTIM2)

The devices embed two low-power timers. These timers have an independent clock and are running in Stop mode if they are clocked by LSE, LSI or an external clock. They are able to wakeup the system from Stop mode.

LPTIM1 is active in Stop 0, Stop 1 and Stop 2 modes.

LPTIM2 is active in Stop 0 and Stop 1 mode.

3.36 Quad SPI memory interface (QUADSPI)

The Quad SPI is a specialized communication interface targeting single, dual or quad SPI flash memories. It can operate in any of the three following modes:

- Indirect mode: all the operations are performed using the QUADSPI registers
- Status polling mode: the external flash status register is periodically read and an interrupt can be generated in case of flag setting
- Memory-mapped mode: the external flash is memory mapped and is seen by the system as if it were an internal memory

The Quad SPI interface supports:

- Three functional modes: indirect, status-polling, and memory-mapped
- SDR and DDR support
- Fully programmable opcode for both indirect and memory mapped mode
- Fully programmable frame format for both indirect and memory mapped mode
- Each of the 5 following phases can be configured independently (enable, length, single/dual/quad communication)
 - Instruction phase
 - Address phase
 - Alternate bytes phase
 - Dummy cycles phase
 - Data phase
- Integrated FIFO for reception and transmission
- 8, 16, and 32-bit data accesses are allowed
- DMA channel for indirect mode operations
- Programmable masking for external flash flag management
- Timeout management
- Interrupt generation on FIFO threshold, timeout, status match, operation complete, and access error

Table 15. STM32L476xxSTM32L476xx pin definitions (continued)

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP64	WLCSP72	WLCSP81	LQFP100	UFPGA132	LQFP144					Alternate functions	Additional functions
-	C5	C5	-	D7	127	PG12	I/O	FT_s	-	LPTIM1_ETR, SPI3_NSS, USART1_RTS_DE, FMC_NE4, SAI2_SD_A, EVENTOUT	-
-	B5	B5	-	C7	128	PG13	I/O	FT_fs	-	I2C1_SDA, USART1_CK, FMC_A24, EVENTOUT	-
-	A5	A5	-	C6	129	PG14	I/O	FT_fs	-	I2C1_SCL, FMC_A25, EVENTOUT	-
-	-	-	-	F7	130	VSS	S	-	-	-	-
-	B6	B6	-	G7	131	VDDIO2	S	-	-	-	-
-	-	-	-	K1	132	PG15	I/O	FT_s	-	LPTIM1_OUT, I2C1_SMBA, EVENTOUT	-
55	A6	A6	89	A8	133	PB3 (JTDO- TRACESWO)	I/O	FT_la	(3)	JTDO-TRACESWO, TIM2_CH2, SPI1_SCK, SPI3_SCK, USART1_RTS_DE, LCD_SEG7, SAI1_SCK_B, EVENTOUT	COMP2_ INM
56	C6	C6	90	A7	134	PB4 (NJTRST)	I/O	FT_la	(3)	NJTRST, TIM3_CH1, SPI1_MISO, SPI3_MISO, USART1_CTS, UART5_RTS_DE, TSC_G2_IO1, LCD_SEG8, SAI1_MCLK_B, TIM17_BKIN, EVENTOUT	COMP2_ INP
57	C7	C7	91	C5	135	PB5	I/O	FT_la	-	LPTIM1_IN1, TIM3_CH2, I2C1_SMBA, SPI1_MOSI, SPI3_MOSI, USART1_CK, UART5_CTS, TSC_G2_IO2, LCD_SEG9, COMP2_OUT, SAI1_SD_B, TIM16_BKIN, EVENTOUT	-
58	B7	B7	92	B5	136	PB6	I/O	FT_fa	-	LPTIM1_ETR, TIM4_CH1, TIM8_BKIN2, I2C1_SCL, DFSDM_DATIN5, USART1_TX, TSC_G2_IO3, TIM8_BKIN2_COMP2, SAI1_FS_B, TIM16_CH1N, EVENTOUT	COMP2_ INP

Table 17. Alternate function AF8 to AF15 (for AF0 to AF7 see [Table 16](#)) (continued)

Port		AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		UART4, UART5, LPUART1	CAN1, TSC	OTG_FS, QUADSPI	LCD	SDMMC1, COMP1, COMP2, FMC, SWPMI1	SAI1, SAI2	TIM2, TIM15, TIM16, TIM17, LPTIM2	EVENTOUT
Port G	PG0	-	TSC_G8_IO3	-	-	FMC_A10	-	-	EVENTOUT
	PG1	-	TSC_G8_IO4	-	-	FMC_A11	-	-	EVENTOUT
	PG2	-	-	-	-	FMC_A12	SAI2_SCK_B	-	EVENTOUT
	PG3	-	-	-	-	FMC_A13	SAI2_FS_B	-	EVENTOUT
	PG4	-	-	-	-	FMC_A14	SAI2_MCLK_B	-	EVENTOUT
	PG5	LPUART1_CTS	-	-	-	FMC_A15	SAI2_SD_B	-	EVENTOUT
	PG6	LPUART1_RTS_DE	-	-	-	-	-	-	EVENTOUT
	PG7	LPUART1_TX	-	-	-	FMC_INT3	-	-	EVENTOUT
	PG8	LPUART1_RX	-	-	-	-	-	-	EVENTOUT
	PG9	-	-	-	-	FMC_NCE3/ FMC_NE2	SAI2_SCK_A	TIM15_CH1N	EVENTOUT
	PG10	-	-	-	-	FMC_NE3	SAI2_FS_A	TIM15_CH1	EVENTOUT
	PG11	-	-	-	-	-	SAI2_MCLK_A	TIM15_CH2	EVENTOUT
	PG12	-	-	-	-	FMC_NE4	SAI2_SD_A	-	EVENTOUT
	PG13	-	-	-	-	FMC_A24	-	-	EVENTOUT
	PG14	-	-	-	-	FMC_A25	-	-	EVENTOUT
	PG15	-	-	-	-	-	-	-	EVENTOUT

6.3 Operating conditions

6.3.1 General operating conditions

Table 22. General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f _{HCLK}	Internal AHB clock frequency	-	0	80	MHz
f _{PCLK1}	Internal APB1 clock frequency	-	0	80	
f _{PCLK2}	Internal APB2 clock frequency	-	0	80	
V _{DD}	Standard operating voltage	-	1.71 (1)	3.6	V
V _{DDIO2}	PG[15:2] I/Os supply voltage	At least one I/O in PG[15:2] used	1.08	3.6	V
		PG[15:2] not used	0	3.6	
V _{DDA}	Analog supply voltage	ADC or COMP used	1.62	3.6	V
		DAC or OPAMP used	1.8		
		VREFBUF used	2.4		
		ADC, DAC, OPAMP, COMP, VREFBUF not used	0		
V _{BAT}	Backup operating voltage	-	1.55	3.6	V
V _{DDUSB}	USB supply voltage	USB used	3.0	3.6	V
		USB not used	0	3.6	
V _{IN}	I/O input voltage	TT_xx I/O	-0.3	V _{DDIOx} +0.3	V
		BOOT0	0	9	
		All I/O except BOOT0 and TT_xx	-0.3	MIN(MIN(V _{DD} , V _{DDA} , V _{DDIO2} , V _{DDUSB} , V _{LCD})+3.6 V, 5.5 V) ⁽²⁾⁽³⁾	
P _D	Power dissipation at T _A = 85 °C for suffix 6 or T _A = 105 °C for suffix 7 ⁽⁴⁾	LQFP144	-	625	mW
		LQFP100	-	476	
		LQFP64	-	444	
		UFBGA132	-	363	
		WLCSP81	-	487	
		WLCSP72	-	434	
P _D	Power dissipation at T _A = 125 °C for suffix 3 ⁽⁴⁾	LQFP144	-	156	mW
		LQFP100	-	119	
		LQFP64	-	111	
		UFBGA132	-	90	
		WLCSP81	-	121	
		WLCSP72	-	108	

Table 22. General operating conditions (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
T _A	Ambient temperature for the suffix 6 version	Maximum power dissipation	−40	85	°C
		Low-power dissipation ⁽⁵⁾	−40	105	
	Ambient temperature for the suffix 7 version	Maximum power dissipation	−40	105	
		Low-power dissipation ⁽⁵⁾	−40	125	
	Ambient temperature for the suffix 3 version	Maximum power dissipation	−40	125	
		Low-power dissipation ⁽⁵⁾	−40	130	
T _J	Junction temperature range	Suffix 6 version	−40	105	°C
		Suffix 7 version	−40	125	
		Suffix 3 version	−40	130	

- When RESET is released functionality is guaranteed down to V_{BOR0} Min.
- This formula has to be applied only on the power supplies related to the IO structure described by the pin definition table. Maximum I/O input voltage is the smallest value between MIN(V_{DD}, V_{DDA}, V_{DDIO2}, V_{DDUSB}, V_{LCD})+3.6 V and 5.5V.
- For operation with voltage higher than Min (V_{DD}, V_{DDA}, V_{DDIO2}, V_{DDUSB}, V_{LCD}) +0.3 V, the internal Pull-up and Pull-Down resistors must be disabled.
- If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_{Jmax} (see [Section 7.7: Thermal characteristics](#)).
- In low-power dissipation state, T_A can be extended to this range as long as T_J does not exceed T_{Jmax} (see [Section 7.7: Thermal characteristics](#)).

6.3.2 Operating conditions at power-up / power-down

The parameters given in [Table 23](#) are derived from tests performed under the ambient temperature condition summarized in [Table 22](#).

Table 23. Operating conditions at power-up / power-down

Symbol	Parameter	Conditions	Min	Max	Unit
t _{VDD}	V _{DD} rise time rate	-	0	∞	μs/V
	V _{DD} fall time rate		10	∞	
t _{VDDA}	V _{DDA} rise time rate	-	0	∞	
	V _{DDA} fall time rate		10	∞	
t _{VDDUSB}	V _{DDUSB} rise time rate	-	0	∞	
	V _{DDUSB} fall time rate		10	∞	
t _{VDDIO2}	V _{DDIO2} rise time rate	-	0	∞	
	V _{DDIO2} fall time rate		10	∞	

6.3.3 Embedded reset and power control block characteristics

The parameters given in [Table 24](#) are derived from tests performed under the ambient temperature conditions summarized in [Table 22: General operating conditions](#).

Table 29. Typical current consumption in Run and Low-power run modes, with different codes running from Flash, ART enable (Cache ON Prefetch OFF)

Symbol	Parameter	Conditions			TYP	Unit	TYP	Unit
		-	Voltage scaling	Code	25 °C		25 °C	
$I_{DD}(\text{Run})$	Supply current in Run mode	$f_{HCLK} = f_{HSE}$ up to 48 MHz included, bypass mode PLL ON above 48 MHz all peripherals disable	Range 2 $f_{HCLK} = 26 \text{ MHz}$	Reduced code ⁽¹⁾	2.9	mA	111	$\mu\text{A}/\text{MHz}$
				Coremark	3.1		118	
				Dhrystone 2.1	3.1		119	
				Fibonacci	2.9		112	
				While(1)	2.8		108	
			Range 1 $f_{HCLK} = 80 \text{ MHz}$	Reduced code ⁽¹⁾	10.2	mA	127	$\mu\text{A}/\text{MHz}$
				Coremark	10.9		136	
				Dhrystone 2.1	11.0		137	
				Fibonacci	10.5		131	
				While(1)	9.9		124	
$I_{DD}(\text{LPRun})$	Supply current in Low-power run	$f_{HCLK} = f_{MSI} = 2 \text{ MHz}$ all peripherals disable		Reduced code ⁽¹⁾	272	μA	136	$\mu\text{A}/\text{MHz}$
				Coremark	291		145	
				Dhrystone 2.1	302		151	
				Fibonacci	269		135	
				While(1)	269		135	

1. Reduced code used for characterization results provided in [Table 26](#), [Table 27](#), [Table 28](#).

Table 37. Current consumption in Standby mode (continued)

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (SRAM2) (⁴)	Supply current to be added in Standby mode when SRAM2 is retained	-	1.8 V	235	641	2293	5192	11213	588	1603	5733	12980	28033	nA
			2.4 V	237	645	2303	5213	11246	593	1613	5758	13033	28115	
			3 V	236	647	2306	5221	11333	593	1618	5765	13053	28333	
			3.6 V	235	646	2308	5200	11327	595	1620	5770	13075	28350	
I _{DD} (wakeup from Standby)	Supply current during wakeup from Standby mode	Wakeup clock is MSI = 4 MHz. See (⁵).	3 V	1.7	-	-	-	-	-					mA

1. Guaranteed by characterization results, unless otherwise specified.
2. Guaranteed by test in production.
3. Based on characterization done with a 32.768 kHz crystal (MC306-G-06Q-32.768, manufacturer JFVNY) with two 6.8 pF loading capacitors.
4. The supply current in Standby with SRAM2 mode is: I_{DD}(Standby) + I_{DD}(SRAM2). The supply current in Standby with RTC with SRAM2 mode is: I_{DD}(Standby + RTC) + I_{DD}(SRAM2).
5. Wakeup with code execution from Flash. Average value given for a typical wakeup time as specified in [Table 41: Low-power mode wakeup timings](#).

Table 38. Current consumption in Shutdown mode

Symbol	Parameter	Conditions		TYP					MAX ⁽¹⁾					Unit
		-	V _{DD}	25 °C	55 °C	85 °C	105 °C	125 °C	25 °C	55 °C	85 °C	105 °C	125 °C	
I _{DD} (Shutdown)	Supply current in Shutdown mode (backup registers retained) RTC disabled	-	1.8 V	29.8	194	1110	3250	9093	75	485	2775	8125	22733	nA
			2.4 V	44.3	237	1310	3798	10473	111	593	3275	9495	26183	
			3 V	64.1	293	1554	4461	12082	160	733	3885	11153	30205	
			3.6 V	112	420	2041	5689	15186	280	1050	5103	14223	37965	

6.3.14 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 58](#) are derived from tests performed under the conditions summarized in [Table 22: General operating conditions](#). All I/Os are designed as CMOS- and TTL-compliant (except BOOT0).

Table 58. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL}^{(1)}$	I/O input low level voltage except BOOT0	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.3 \times V_{DDIOx}^{(2)}$	V
	I/O input low level voltage except BOOT0	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.39 \times V_{DDIOx} - 0.06^{(3)}$	
	I/O input low level voltage except BOOT0	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	-	-	$0.43 \times V_{DDIOx} - 0.1^{(3)}$	
	BOOT0 I/O input low level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	-	$0.17 \times V_{DDIOx}^{(3)}$	
$V_{IH}^{(1)}$	I/O input high level voltage except BOOT0	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.7 \times V_{DDIOx}^{(2)}$	-	-	V
	I/O input high level voltage except BOOT0	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.49 \times V_{DDIOx} + 0.26^{(3)}$	-	-	
	I/O input high level voltage except BOOT0	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	$0.61 \times V_{DDIOx} + 0.05^{(3)}$	-	-	
	BOOT0 I/O input high level voltage	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	$0.77 \times V_{DDIOx}^{(3)}$	-	-	
$V_{hys}^{(3)}$	TT_xx, FT_xxx and NRST I/O input hysteresis	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	200	-	mV
	FT_sx	$1.08\text{ V} < V_{DDIOx} < 1.62\text{ V}$	-	150	-	
	BOOT0 I/O input hysteresis	$1.62\text{ V} < V_{DDIOx} < 3.6\text{ V}$	-	200	-	

6.3.25 DFSDM characteristics

Unless otherwise specified, the parameters given in [Table 78](#) for DFSDM are derived from tests performed under the ambient temperature, f_{APB2} frequency and V_{DD} supply voltage conditions summarized in [Table 22: General operating conditions](#).

- Output speed is set to $OSPEEDRy[1:0] = 10$
- Capacitive load $C = 30$ pF
- Measurement points are done at CMOS levels: $0.5 \times V_{DD}$

Refer to [Section 6.3.14: I/O port characteristics](#) for more details on the input/output alternate function characteristics (DFSDM_CKINy, DFSDM_DATINy, DFSDM_CKOUT for DFSDM).

Table 78. DFSDM characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{DFSDMCLK}$	DFSDM clock	-	-	-	f_{SYSCLK}	MHz
f_{CKIN} ($1/T_{CKIN}$)	Input clock frequency	SPI mode (SITP[1:0] = 01)	-	-	20 ($f_{DFSDMCLK}/4$)	
f_{CKOUT}	Output clock frequency	-	-	-	20	MHz
$DuCy_{CKOUT}$	Output clock frequency duty cycle	-	45	50	55	%
$t_{wh(CKIN)}$ $t_{wl(CKIN)}$	Input clock high and low time	SPI mode (SITP[1:0] = 01), External clock mode (SPICKSEL[1:0] = 0)	$T_{CKIN}/2-0.5$	$T_{CKIN}/2$	-	ns
t_{su}	Data input setup time	SPI mode (SITP[1:0]=01), External clock mode (SPICKSEL[1:0] = 0)	0	-	-	
t_h	Data input hold time	SPI mode (SITP[1:0]=01), External clock mode (SPICKSEL[1:0] = 0)	2	-	-	
$T_{Manchester}$	Manchester data period (recovered clock period)	Manchester mode (SITP[1:0] = 10 or 11), Internal clock mode (SPICKSEL[1:0] $\neq$ 0)	$(CKOUT DIV+1) \times T_{DFSDMCLK}$	-	$(2 \times CKOUTDIV) \times T_{DFSDMCLK}$	

1. Data based on characterization results, not tested in production.

Table 79. TIMx⁽¹⁾ characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
t _{res(TIM)}	Timer resolution time	-	1	-	t _{TIMxCLK}
		f _{TIMxCLK} = 80 MHz	12.5	-	ns
f _{EXT}	Timer external clock frequency on CH1 to CH4	-	0	f _{TIMxCLK} /2	MHz
		f _{TIMxCLK} = 80 MHz	0	40	MHz
Res _{TIM}	Timer resolution	TIMx (except TIM2 and TIM5)	-	16	bit
		TIM2 and TIM5	-	32	
t _{COUNTER}	16-bit counter clock period	-	1	65536	t _{TIMxCLK}
		f _{TIMxCLK} = 80 MHz	0.0125	819.2	μs
t _{MAX_COUNT}	Maximum possible count with 32-bit counter	-	-	65536 × 65536	t _{TIMxCLK}
		f _{TIMxCLK} = 80 MHz	-	53.68	s

1. TIMx is used as a general term in which x stands for 1,2,3,4,5,6,7,8,15,16 or 17.

Table 80. IWDG min/max timeout period at 32 kHz (LSI)⁽¹⁾

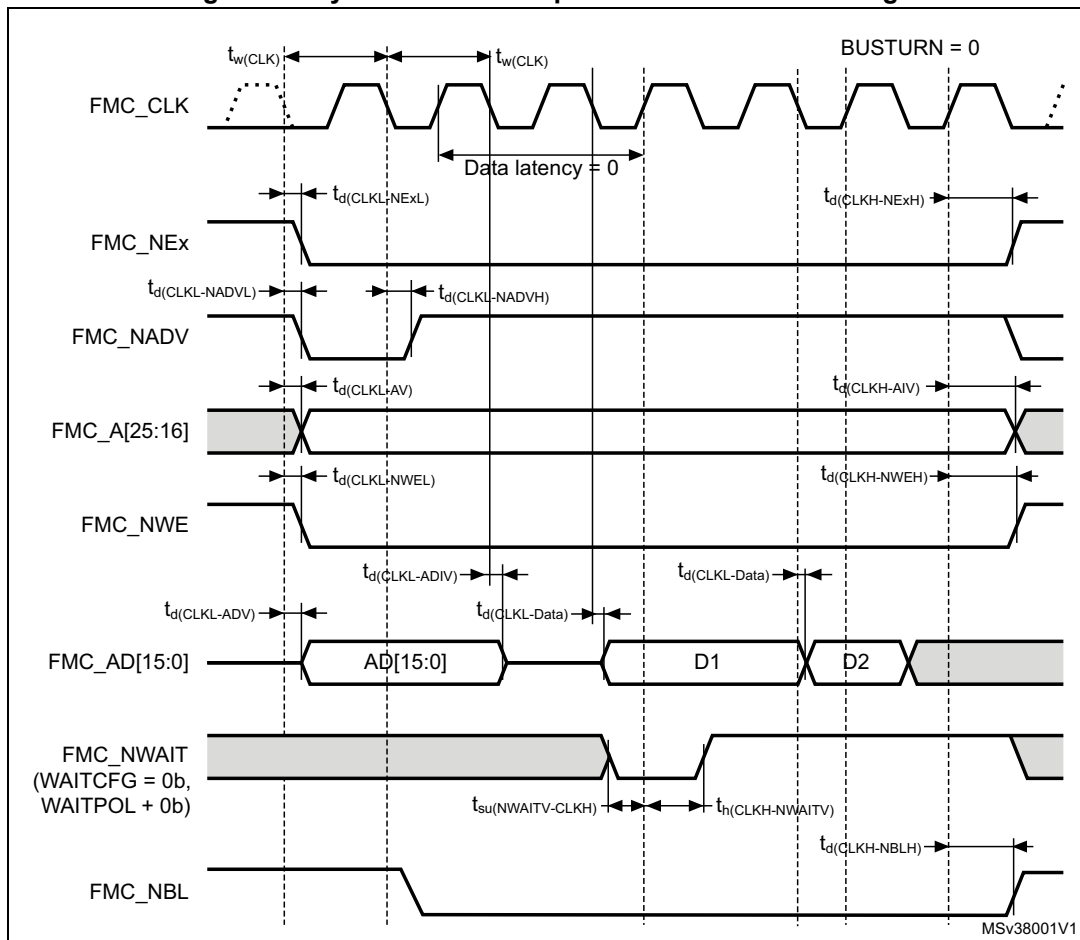
Prescaler divider	PR[2:0] bits	Min timeout RL[11:0]= 0x000	Max timeout RL[11:0]= 0xFFFF	Unit
/4	0	0.125	512	ms
/8	1	0.250	1024	
/16	2	0.500	2048	
/32	3	1.0	4096	
/64	4	2.0	8192	
/128	5	4.0	16384	
/256	6 or 7	8.0	32768	

1. The exact timings still depend on the phasing of the APB interface clock versus the LSI clock so that there is always a full RC period of uncertainty.

Table 81. WWDG min/max timeout value at 80 MHz (PCLK)

Prescaler	WDGTB	Min timeout value	Max timeout value	Unit
1	0	0.0512	3.2768	ms
2	1	0.1024	6.5536	
4	2	0.2048	13.1072	
8	3	0.4096	26.2144	

Figure 42. Synchronous multiplexed PSRAM write timings



1. CL = 30 pF.
2. Guaranteed by characterization results.

Figure 44. Synchronous non-multiplexed PSRAM write timings

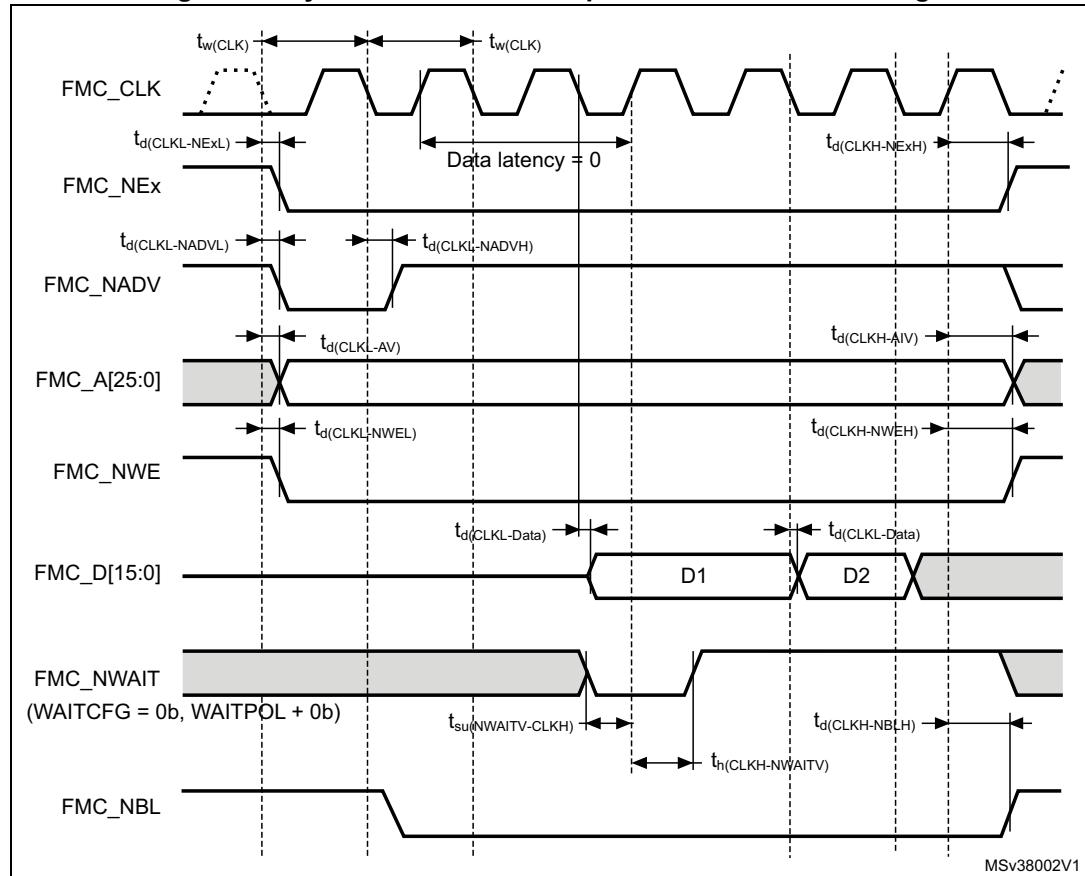
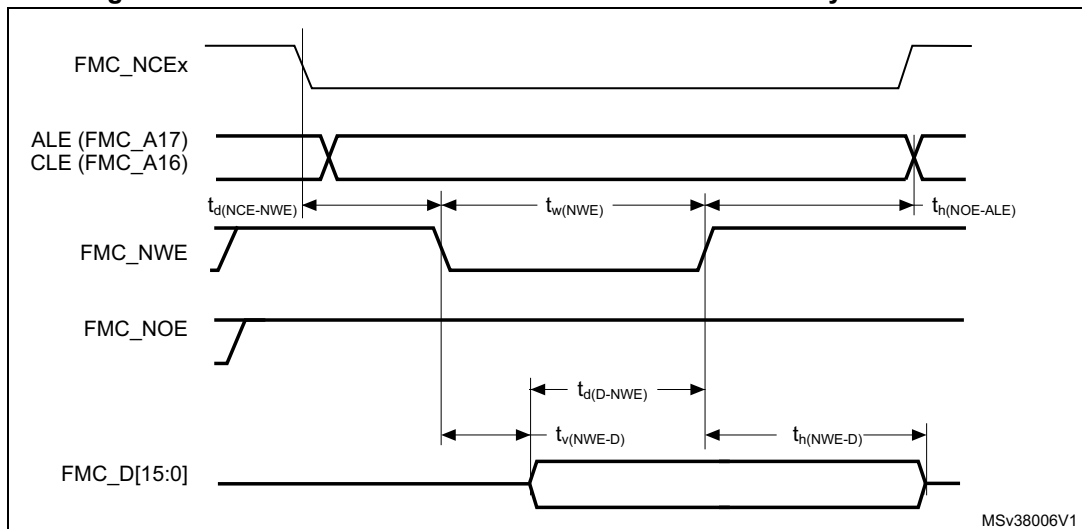


Figure 48. NAND controller waveforms for common memory write access**Table 102. Switching characteristics for NAND Flash read cycles⁽¹⁾⁽²⁾**

Symbol	Parameter	Min	Max	Unit
$T_{w(NOE)}$	FMC_NOE low width	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$T_{su(D-NOE)}$	FMC_D[15-0] valid data before FMC_NOE high	16	-	
$T_{h(NOE-D)}$	FMC_D[15-0] valid data after FMC_NOE high	6	-	
$T_{d(NCE-NOE)}$	FMC_NCE valid before FMC_NOE low	-	$3T_{HCLK}+1$	
$T_{h(NOE-ALE)}$	FMC_NOE high to FMC_ALE invalid	$2T_{HCLK}-2$	-	

1. CL = 30 pF.

2. Guaranteed by characterization results.

Table 103. Switching characteristics for NAND Flash write cycles⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
$T_{w(NWE)}$	FMC_NWE low width	$4T_{HCLK}-1$	$4T_{HCLK}+1$	ns
$T_{v(NWE-D)}$	FMC_NWE low to FMC_D[15-0] valid	-	2.5	
$T_{h(NWE-D)}$	FMC_NWE high to FMC_D[15-0] invalid	$3T_{HCLK}-4$	-	
$T_{d(D-NWE)}$	FMC_D[15-0] valid before FMC_NWE high	$5T_{HCLK}-3$	-	
$T_{d(NCE-NWE)}$	FMC_NCE valid before FMC_NWE low	-	$3T_{HCLK}+1$	
$T_{h(NWE-ALE)}$	FMC_NWE high to FMC_ALE invalid	$2T_{HCLK}-2$	-	

1. CL = 30 pF.

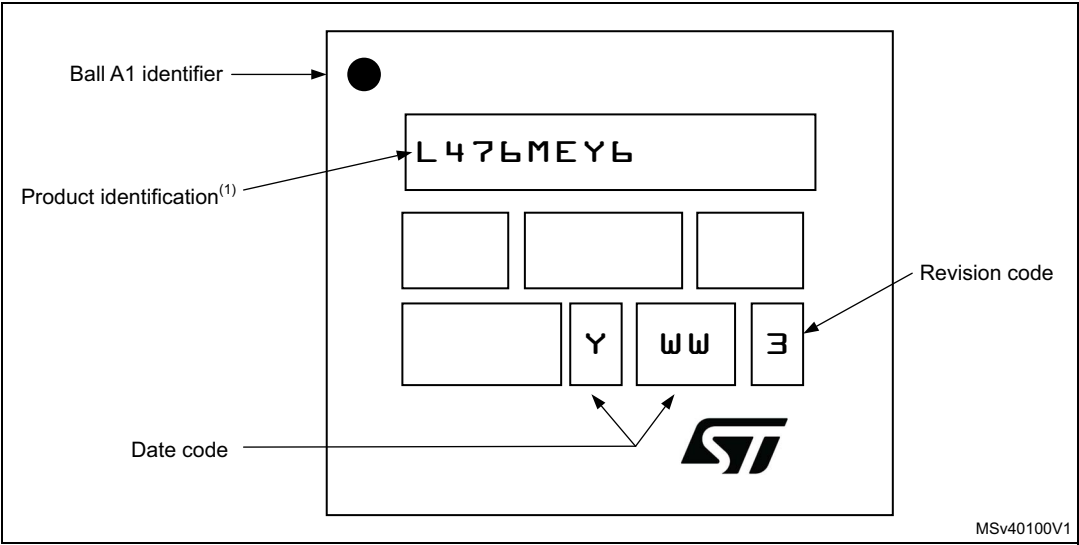
2. Guaranteed by characterization results.

**Table 104. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package
mechanical data**

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.8740
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	-	17.500	-	-	0.6890	-
E	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	-	17.500	-	-	0.6890	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

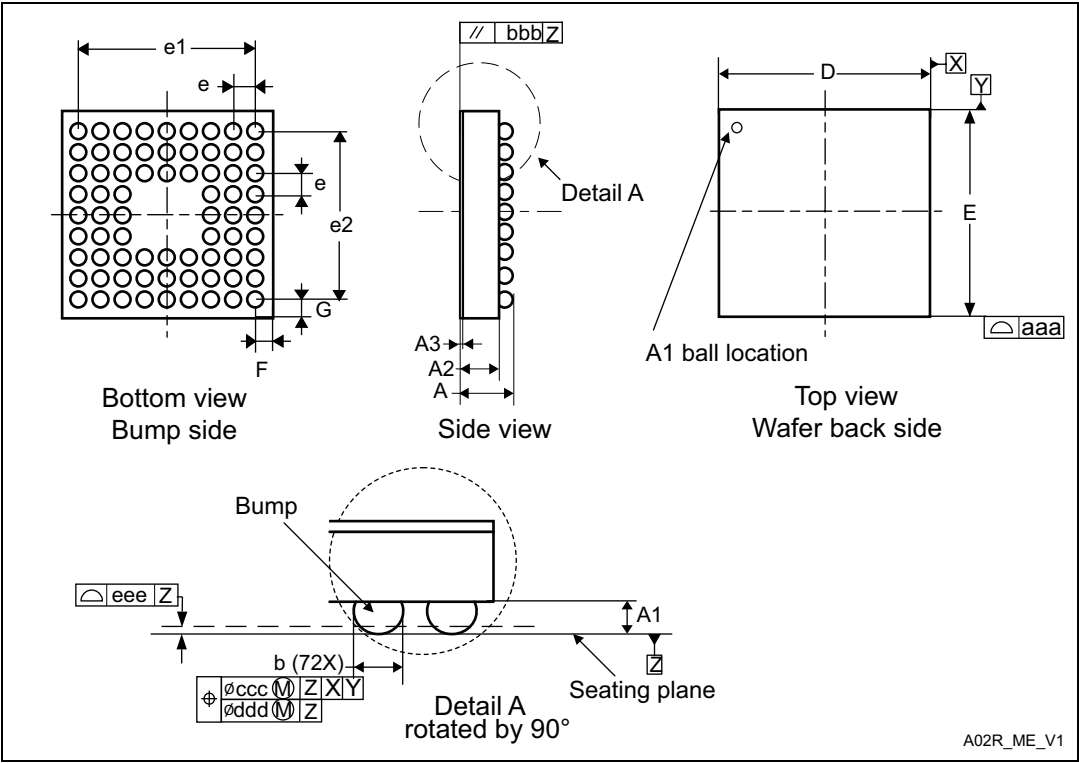
1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 60. WLCSP81 marking (package top view)



7.5 WLCSP72 package information

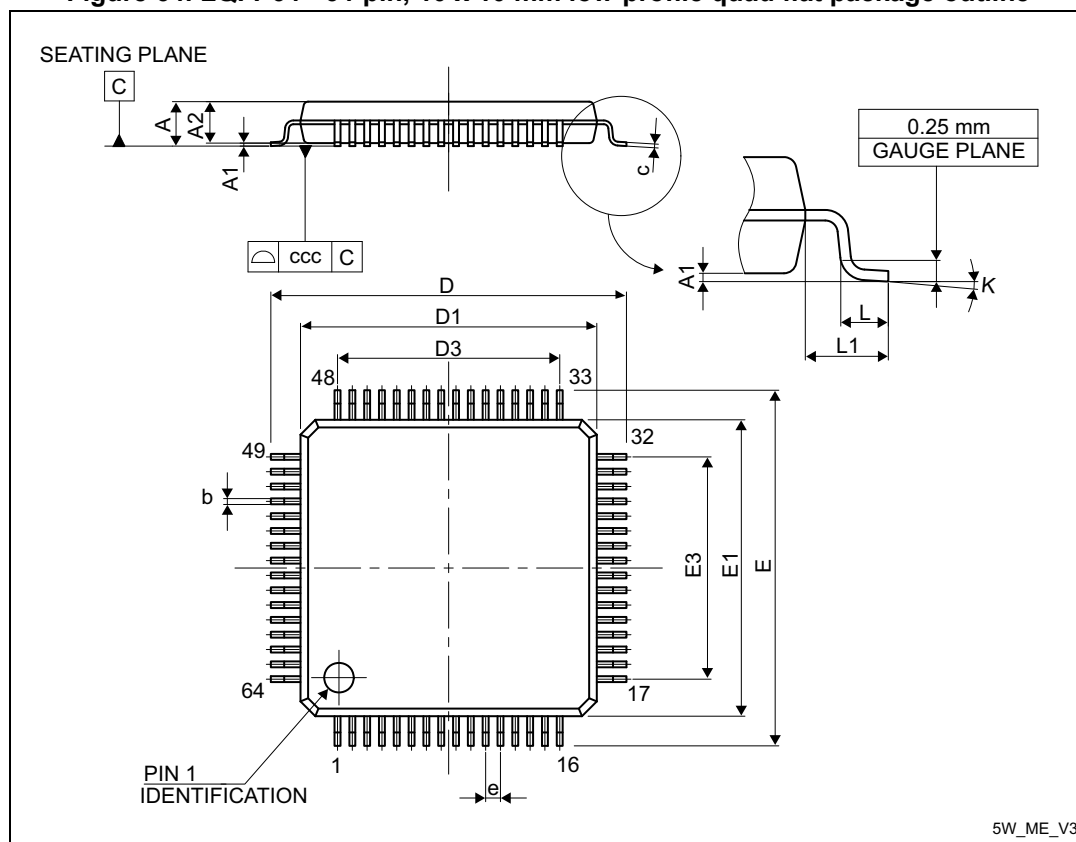
Figure 61. WLCSP72 - 72-ball, 4.4084 x 3.7594 mm, 0.4 mm pitch wafer level chip scale package outline



1. Drawing is not to scale.

7.6 LQFP64 package information

Figure 64. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package outline



1. Drawing is not to scale.

Table 112. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-